

Form 1449*

INFORMATION DISCLOSURE STATEMENT
IN AN APPLICATION FOR PATENT

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Applicants: Jri Lee et al.

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Group Art Unit: 2916

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
W			M. Wurzer et al, "A 40-Gb/s Integrated Clock and Data Recovery Circuit in a 50-GHz f_T Silicon Bipolar Technology," IEEE Journal of Solid-State Circuits, Sept. 1999, 34:1320-1324				
W			M. Reinhold et al, "A Fully Integrated 40-Gb/s Clock and Data Recovery IC with 1:4 DEMUX in SiGe technology," IEEE Journal of Solid-State Circuits, Dec. 2001, 36:1937-1945				
W			J. Cao et al, "OC-192 Receiver in Standard 0.18 μ m CMOS," ISSCC Dig. Tech. Papers, Feb. 2002, pp. 250-251				
W			J. Kim and B. Kim, "A Low Phase-Noise CMOS LC Oscillator with a Ring Structure," ISSCC Dig. of Tech. Papers, Feb. 2000, pp. 430-431				
W			T. P. Liu, "A 6.5-GHz Monolithic CMOS Voltage-Controlled Oscillator," ISSCC Dig. of Tech. Papers, Feb. 1999, pp. 404-405				
W			J. E. Rogers and J. R. Long, "A 10-Gb/s CDR/DEMUX with LC Delay Line VCO in 0.18 μ m CMOS," ISSCC Dig. of Tech. Papers, Feb. 2002, pp. 254-255				
W			J. Savoj and B. Razavi, "A 10-Gb/s CMOS Clock and Data Recovery Circuit with Frequency Detection," ISSCC Dig. Tech. Papers, Feb. 2001, pp. 78-79				
W			M. Danesh et al, "A Q-Factor Enhancement Technique for MMIC Inductors," Proc. IEEE Radio Frequency Integrated Circuits Symp., April 1998, pp. 217-220				
W			A. Hajimiri and T. H. Lee, "A General Theory of Phase Noise in Electrical Oscillators," IEEE Journal of Solid-State Circuits, Feb. 1998, pp. 179-194				
W			J. D. H. Alexander, "Clock Recovery from Random Binary Data," Electronics Letters, Oct. 1975, 11:541-542				
W			B. Razavi et al, "Design Techniques for Low-Voltage High-Speed Digital Bipolar Circuits," IEEE Journal of Solid-State Circuits, March 1994, pp. 332-9				

EXAMINER: <u>[Signature]</u>	DATE CONSIDERED: <u>2/16</u>
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.	